

Features

- Uses CRM(CQ) advanced Trench technology
- Extremely low on-resistance $R_{DS(on)}$
- Excellent $Q_g \times R_{DS(on)}$ product(FOM)
- Qualified according to JEDEC criteria

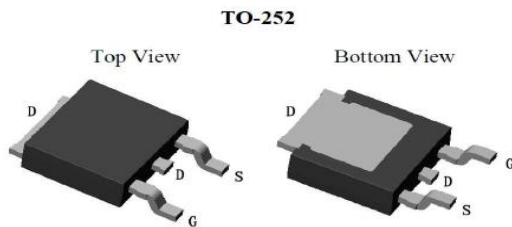
Product Summary

V_{DS}	30V
$R_{DS(on),typ}$	2.8mΩ
I_D	100A

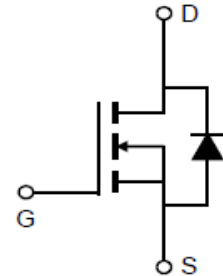
Applications

- Motor control and drive
- Battery management System
- UPS (Uninterruptible Power Supplies)

100% DVDS Tested
100% Avalanche Tested



CRTD038N03L4A



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRTD038N03L4A	CRTD038N03L	TO-252	Tape	N/A	N/A	2500pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	30	V
Continuous drain current $T_C = 25^\circ\text{C}$ (Silicon limit) $T_C = 25^\circ\text{C}$ (Package limit) $T_C = 100^\circ\text{C}$ (Silicon limit)	I_D	100 60 63	A
Pulsed drain current ($T_C = 25^\circ\text{C}$, t_p limited by T_{jmax})	$I_{D\ pulse}$	240	A
Avalanche energy, single pulse ($I_D = 27\text{A}$, $R_g = 25\Omega$) ^[1]	E_{AS}	180	mJ
Gate-Source voltage	V_{GS}	± 20	V
Power dissipation ($T_C = 25^\circ\text{C}$)	P_{tot}	77	W
Operating junction and storage temperature	T_j, T_{stg}	-55...+150	$^\circ\text{C}$
Soldering temperature, wave soldering only allowed at leads (1.6mm from case for 10s)	T_{sold}	260	$^\circ\text{C}$

※. Notes:

1.EAS is tested at starting $T_j = 25^\circ\text{C}$, $L = 0.5\text{mH}$, $I_{AS} = 27\text{A}$, $V_{GS} = 10\text{V}$.

2.Repetitive rating, pulse width limited by junction temperature $T_J(\text{MAX}) = 150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J = 25^\circ\text{C}$.

Thermal Resistance

Parameter	Symbol	Max	Unit
Thermal resistance, junction – case.	R_{thJC}	1.62	°C/W
Thermal resistance, junction – ambient(min. footprint)	R_{thJA}	62.5	

Electrical Characteristic (at $T_j = 25\text{ °C}$, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	BV_{DSS}	30	-	-	V	$V_{GS}=0V, I_D=250\mu A$
		30	-	-	V	$V_{GS}=0V, I_D=1mA$
Gate threshold voltage	$V_{GS(th)}$	0.9	1.3	2.0	V	$V_{DS}=V_{GS}, I_D=250\mu A$
Zero gate voltage drain current	I_{DSS}	-	-	1	μA	$V_{DS}=30V, V_{GS}=0V$ $T_j=25\text{ °C}$
		-	-	100		$T_j=125\text{ °C}$
Gate-source leakage current	I_{GSS}	0	-	± 100	nA	$V_{GS}=\pm 20V, V_{DS}=0V$
Drain-source on-state resistance	$R_{DS(on)}$	-	2.8	3.6		$V_{GS}=10V, I_D=19A$
		-	3.8	4.8		$V_{GS}=4.5V, I_D=19A$
Transconductance	g_{fs}	-	57.6	-	S	$V_{DS}=5V, I_D=19A$

Dynamic Characteristic

Input Capacitance	C_{iss}	-	2582	-	pF	$V_{GS}=0V, V_{DS}=15V,$ $f=1MHz$
Output Capacitance	C_{oss}	-	302	-		
Reverse Transfer Capacitance	C_{rss}	-	281	-		
Gate Total Charge	Q_G	-	55.3	-	nC	$V_{GS}=10V, V_{DS}=15V,$ $I_D=19A$
Gate-Source charge	Q_{gs}	-	6.0	-		
Gate-Drain charge	Q_{gd}	-	11.0	-		
Turn-on delay time	$t_{d(on)}$	-	16.8	-	ns	$V_{GS}=10V, V_{DD}=15V,$ $R_{G_ext}=2.5\Omega$
Rise time	t_r	-	8.4	-		
Turn-off delay time	$t_{d(off)}$	-	68.4	-		
Fall time	t_f	-	10.4	-		
Gate resistance	R_G	-	2.0	-	Ω	$V_{GS}=0V, V_{DS}=0V,$ $f=1MHz$

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	-	0.82	1.4	V	$V_{GS}=0V, I_{SD}=19A$
Body Diode Reverse Recovery Time	t_{rr}	-	42.4	-	ns	$I_F=19A, dI/dt=100A/\mu s$
Body Diode Reverse Recovery Charge	Q_{rr}	-	35.0	-	nC	

Typical Performance Characteristics

Fig 1: Output Characteristics

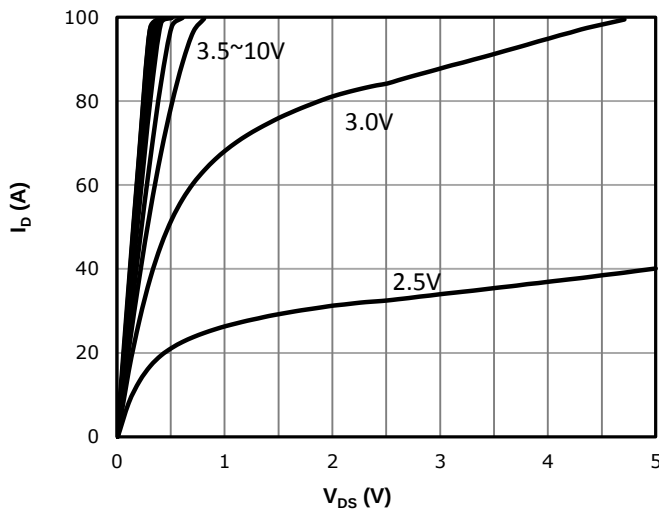


Fig 2: Transfer Characteristics

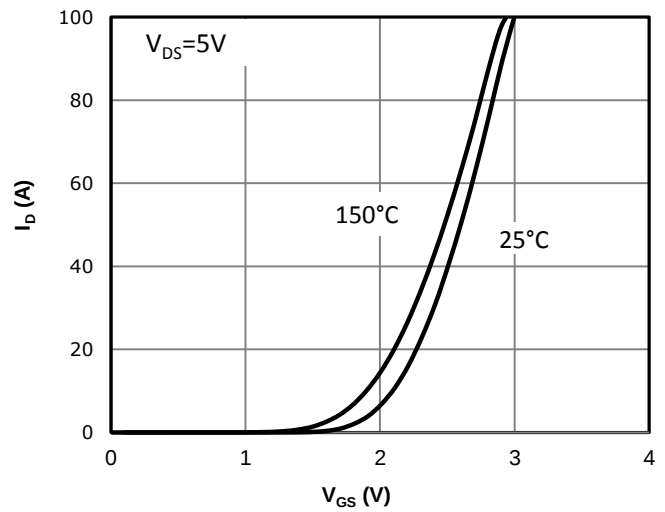
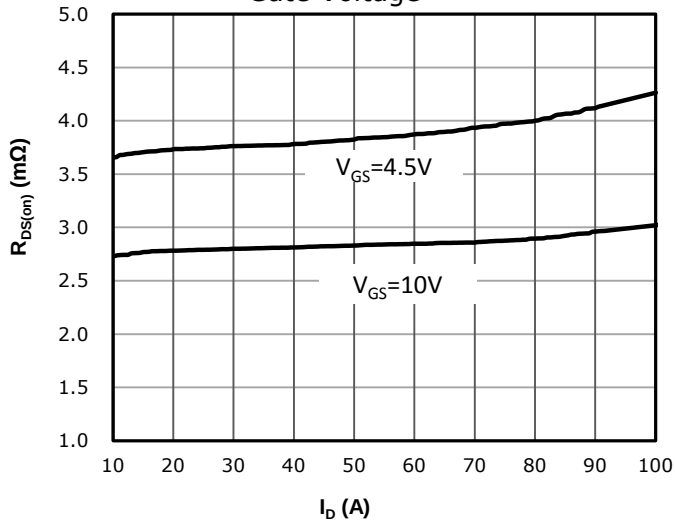
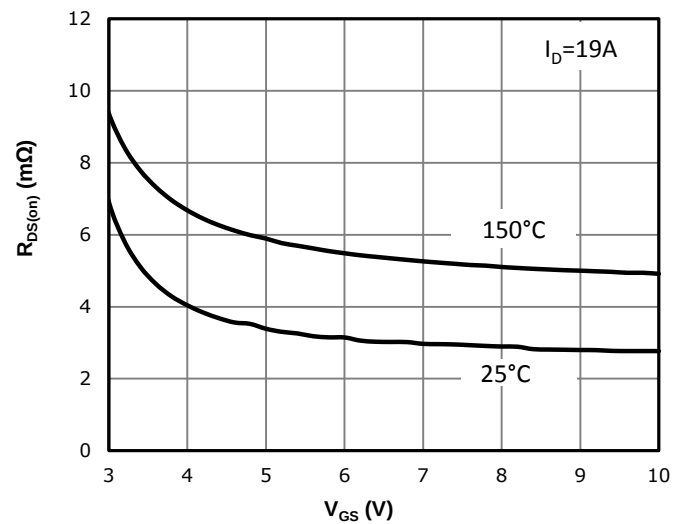
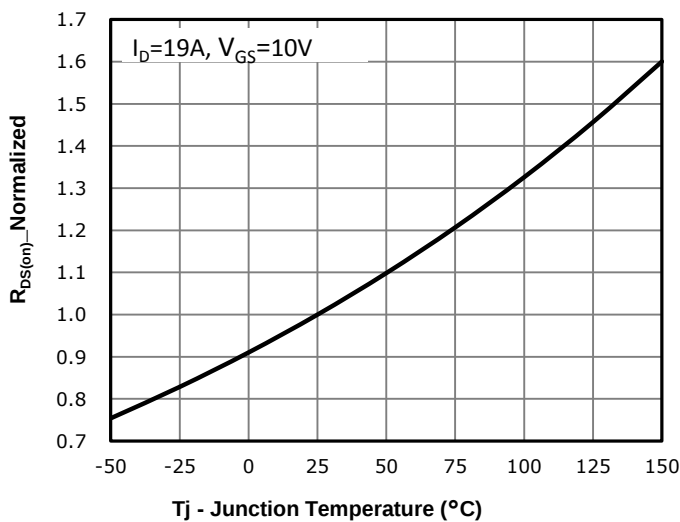
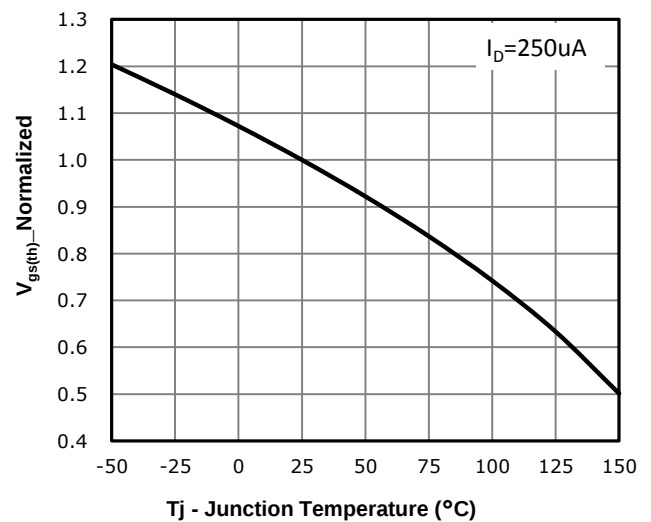

Fig 3: $R_{DS(on)}$ vs Drain Current and Gate Voltage

Fig 4: $R_{DS(on)}$ vs Gate Voltage

Fig 5: $R_{DS(on)}$ vs. Temperature

Fig 6: $V_{GS(th)}$ vs. Temperature


Fig 7: BVdss vs. Temperature

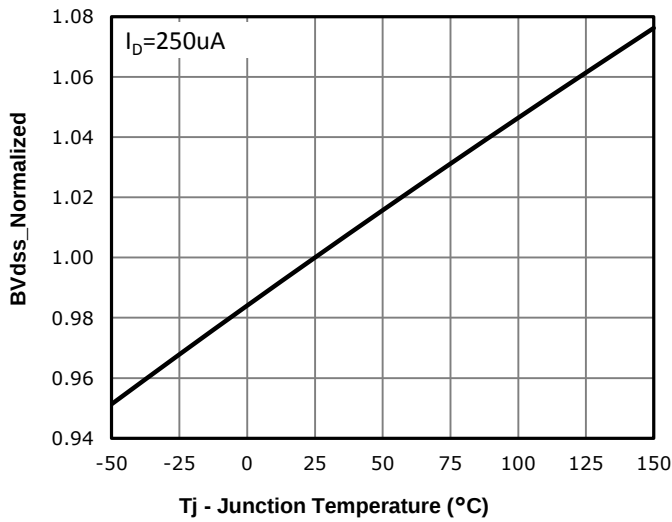


Fig 8: Capacitance Characteristics

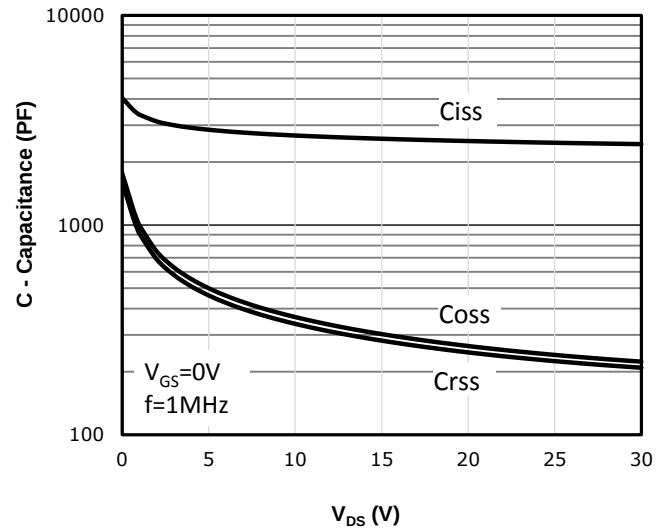


Fig 9: Gate Charge Characteristics

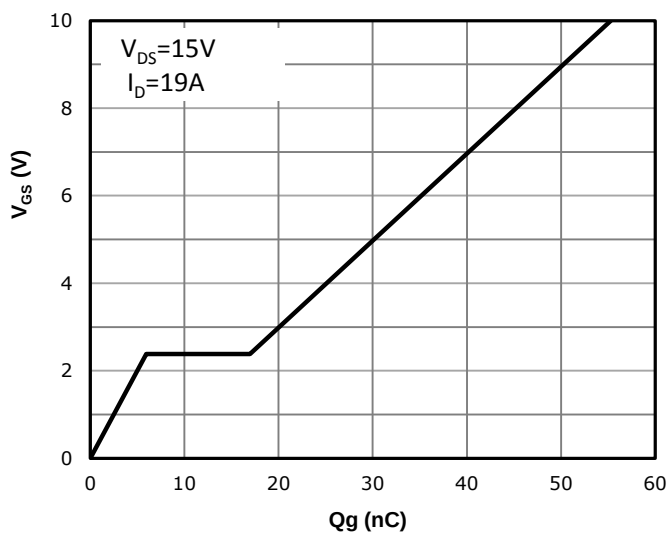


Fig 10: Body-diode Forward Characteristics

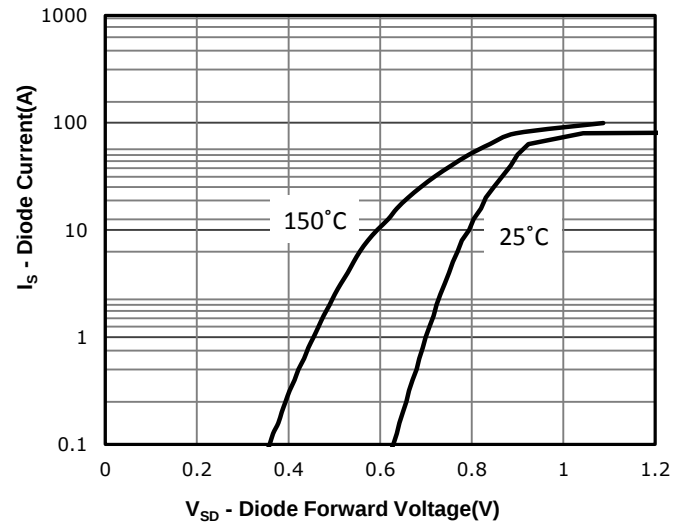


Fig 11: Power Dissipation

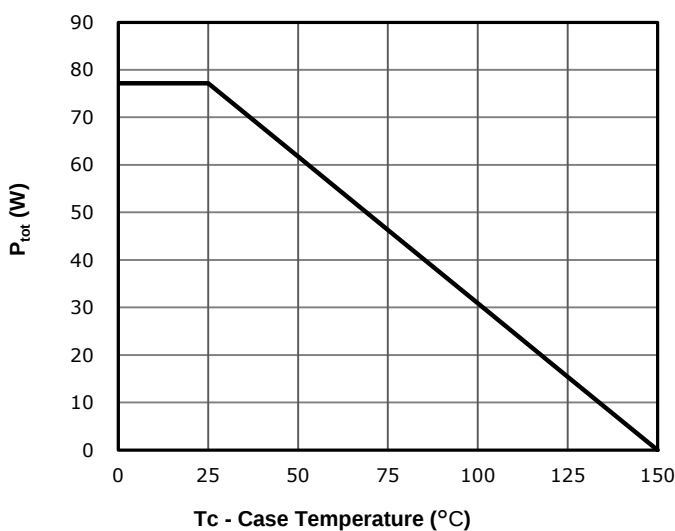


Fig 12: Drain Current Derating

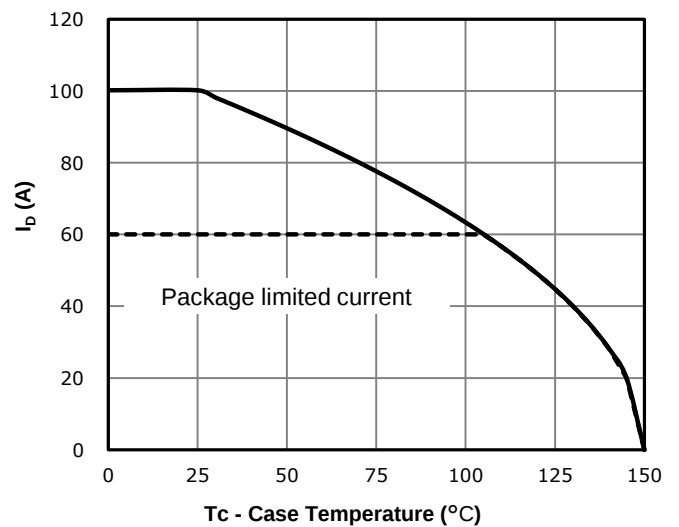


Fig 13: Safe Operating Area

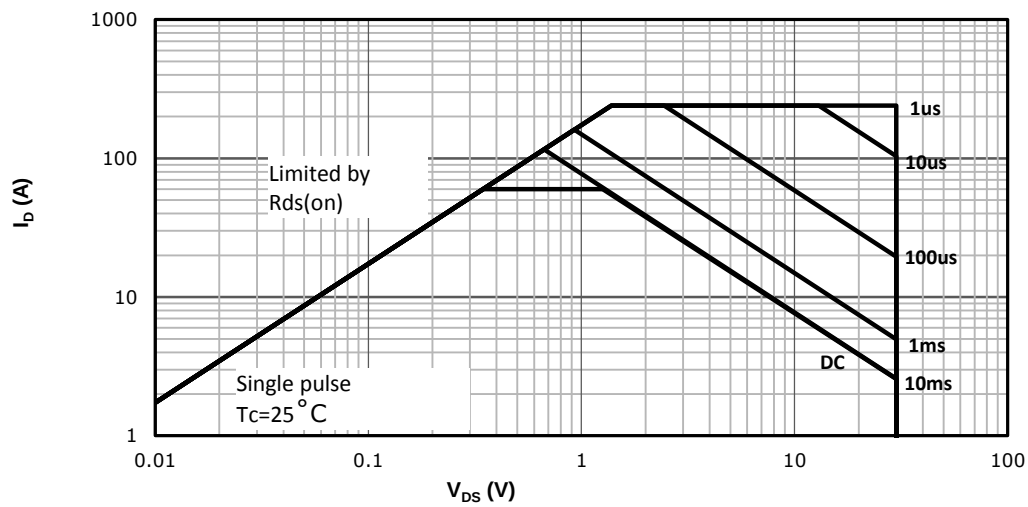
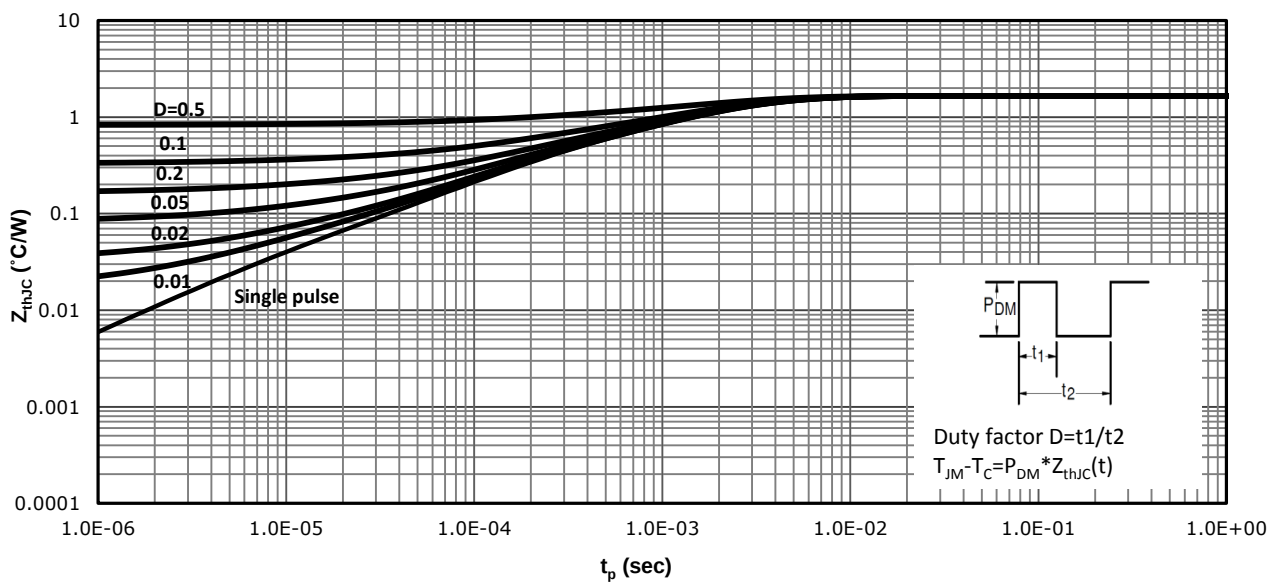
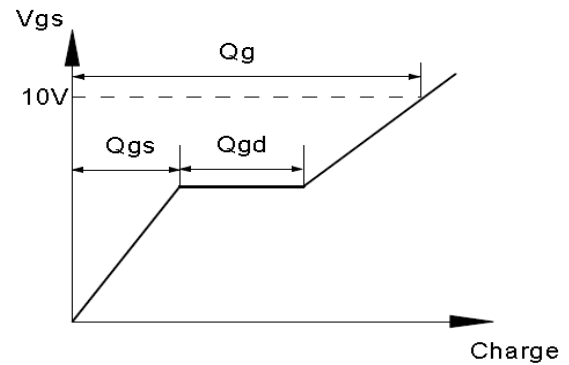
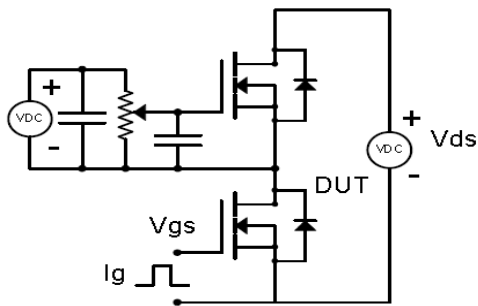


Fig 14: Max. Transient Thermal Impedance

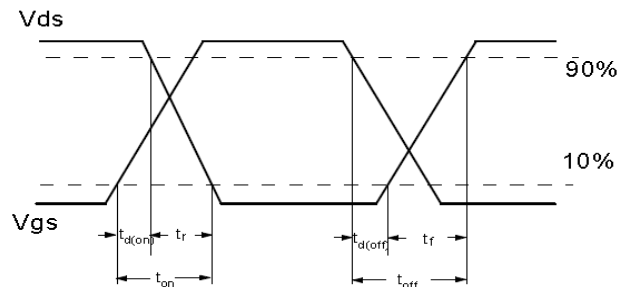
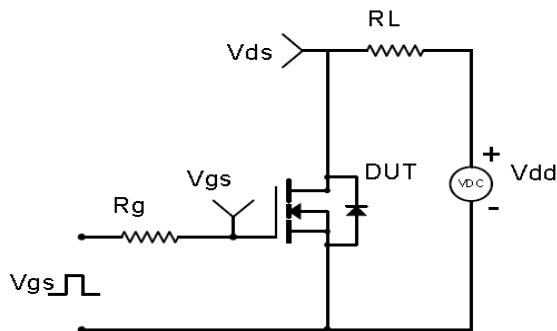


Test Circuit & Waveform

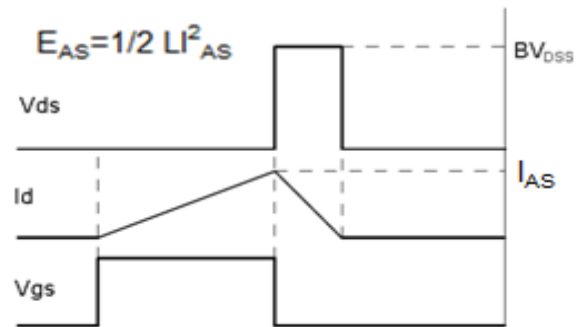
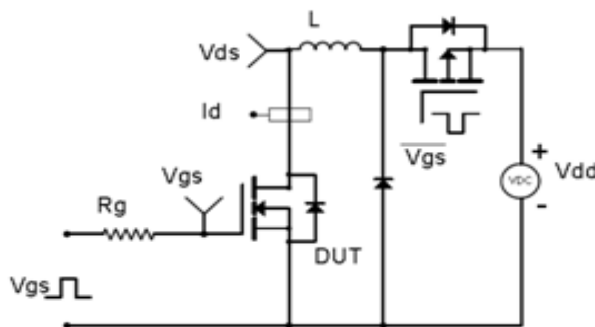
Gate Charge Test Circuit & Waveform



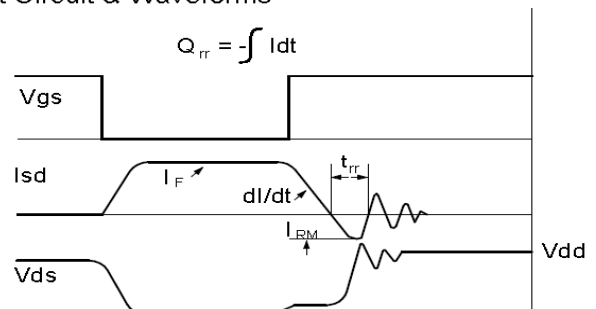
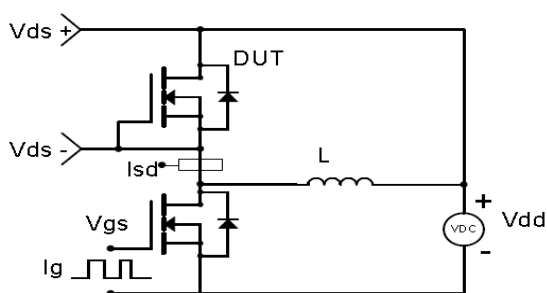
Resistive Switching Test Circuit & Waveforms



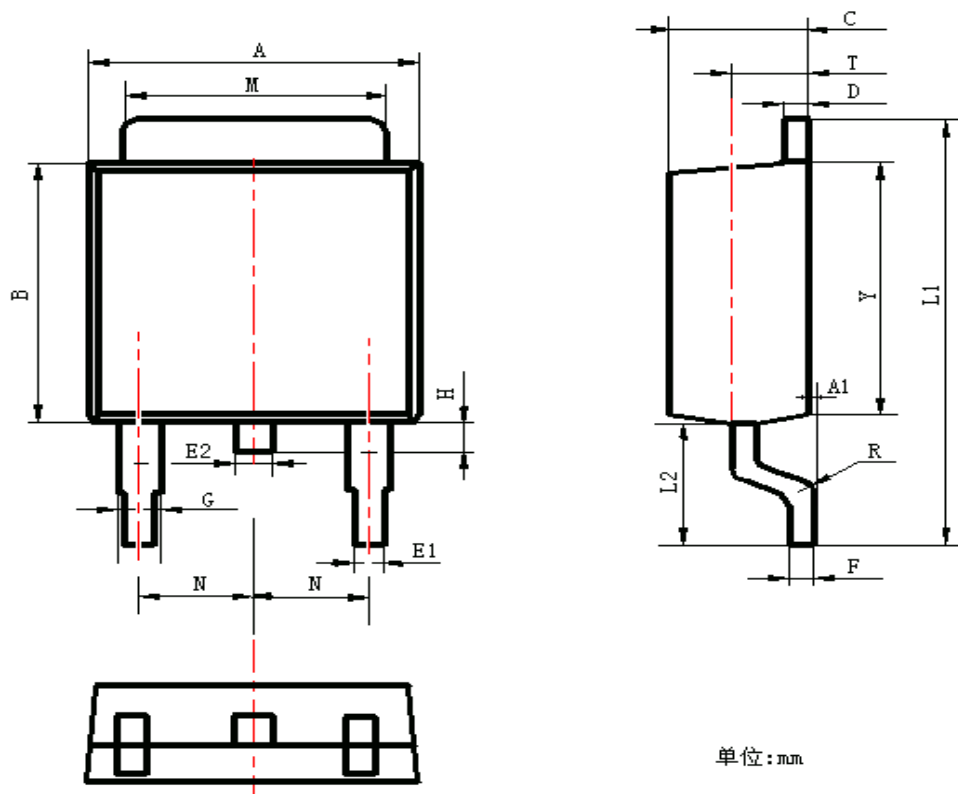
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Outline: TO-252



Symbol	Values(mm)	
	Min.	Max.
A	6.300	6.900
A1	0.000	0.160
B	5.700	6.300
C	2.100	2.500
D	0.300	0.700
E1	0.600	0.900
E2	0.700	1.000
F	0.300	0.600
G	0.700	1.200
L1	9.600	10.500
L2	2.700	3.100
H	0.400	1.000
M	5.100	5.500
N	2.090	2.490
R	0.300	
T	1.400	1.600
Y	5.100	6.300

Marking



NOTE:
AABXXXG
AA —cycle code
B —Fab code
XXX —Assembly lot code

Revision History

Revision	Date	Major changes
1.0	2024/6/24	Release of Preliminary version

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.